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**Understanding Embedded - CPLDs (Complex Programmable Logic Devices)** 

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

# **Applications of Embedded - CPLDs**

Details	
Product Status	Obsolete
Programmable Type	EE PLD
Delay Time tpd(1) Max	12 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	12
Number of Macrocells	192
Number of Gates	3750
Number of I/O	124
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	160-BQFP
Supplier Device Package	160-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7192eqc160-12yy

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

- Additional design entry and simulation support provided by EDIF 2 0 0 and 3 0 0 netlist files, library of parameterized modules (LPM), Verilog HDL, VHDL, and other interfaces to popular EDA tools from manufacturers such as Cadence, Exemplar Logic, Mentor Graphics, OrCAD, Synopsys, and VeriBest
- Programming support
  - Altera's Master Programming Unit (MPU) and programming hardware from third-party manufacturers program all MAX 7000 devices
  - The BitBlaster<sup>TM</sup> serial download cable, ByteBlasterMV<sup>TM</sup> parallel port download cable, and MasterBlaster<sup>TM</sup> serial/universal serial bus (USB) download cable program MAX 7000S devices

# General Description

The MAX 7000 family of high-density, high-performance PLDs is based on Altera's second-generation MAX architecture. Fabricated with advanced CMOS technology, the EEPROM-based MAX 7000 family provides 600 to 5,000 usable gates, ISP, pin-to-pin delays as fast as 5 ns, and counter speeds of up to 175.4 MHz. MAX 7000S devices in the -5, -6, -7, and -10 speed grades as well as MAX 7000 and MAX 7000E devices in -5, -6, -7, -10P, and -12P speed grades comply with the PCI Special Interest Group (PCI SIG) *PCI Local Bus Specification, Revision 2.2.* See Table 3 for available speed grades.

Device					Speed	l Grade				
	-5	-6	-7	-10P	-10	-12P	-12	-15	-15T	-20
EPM7032		<b>✓</b>	<b>✓</b>		<b>✓</b>		<b>✓</b>	<b>✓</b>	<b>✓</b>	
EPM7032S	<b>✓</b>	<b>✓</b>	<b>✓</b>		<b>✓</b>					
EPM7064		<b>✓</b>	<b>✓</b>		~		<b>✓</b>	<b>✓</b>		
EPM7064S	<b>✓</b>	<b>✓</b>	<b>✓</b>		~					
EPM7096			<b>✓</b>		~		<b>✓</b>	<b>✓</b>		
EPM7128E			<b>✓</b>	<b>✓</b>	~		<b>✓</b>	<b>✓</b>		<b>✓</b>
EPM7128S		<b>✓</b>	<b>✓</b>		~			<b>✓</b>		
EPM7160E				<b>✓</b>	<b>✓</b>		<b>✓</b>	<b>✓</b>		<b>✓</b>
EPM7160S		<b>✓</b>	<b>✓</b>		~			<b>✓</b>		
EPM7192E						<b>✓</b>	<b>✓</b>	<b>✓</b>		<b>✓</b>
EPM7192S			<b>✓</b>		<b>✓</b>			<b>✓</b>		
EPM7256E						<b>✓</b>	<b>✓</b>	<b>✓</b>		<b>✓</b>
EPM7256S			<b>✓</b>		<b>✓</b>			<b>✓</b>		

The MAX 7000 architecture supports 100% TTL emulation and high-density integration of SSI, MSI, and LSI logic functions. The MAX 7000 architecture easily integrates multiple devices ranging from PALs, GALs, and 22V10s to MACH and pLSI devices. MAX 7000 devices are available in a wide range of packages, including PLCC, PGA, PQFP, RQFP, and TQFP packages. See Table 5.

Table 5. M.	AX 7000	) Maxim	um Use	r I/O Pii	ıs N	ote (1)						
Device	44- Pin PLCC	44- Pin PQFP	44- Pin TQFP	68- Pin PLCC	84- Pin PLCC	100- Pin PQFP	100- Pin TQFP	160- Pin PQFP	160- Pin PGA	192- Pin PGA	208- Pin PQFP	208- Pin RQFP
EPM7032	36	36	36									
EPM7032S	36		36									
EPM7064	36		36	52	68	68						
EPM7064S	36		36		68		68					
EPM7096				52	64	76						
EPM7128E					68	84		100				
EPM7128S					68	84	84 (2)	100				
EPM7160E					64	84		104				
EPM7160S					64		84 (2)	104				
EPM7192E								124	124			
EPM7192S								124				
EPM7256E								132 (2)		164		164
EPM7256S											164 (2)	164

#### Notes:

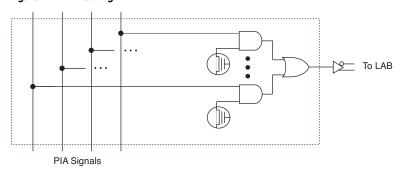
- When the JTAG interface in MAX 7000S devices is used for either boundary-scan testing or for ISP, four I/O pins become JTAG pins.
- (2) Perform a complete thermal analysis before committing a design to this device package. For more information, see the Operating Requirements for Altera Devices Data Sheet.

MAX 7000 devices use CMOS EEPROM cells to implement logic functions. The user-configurable MAX 7000 architecture accommodates a variety of independent combinatorial and sequential logic functions. The devices can be reprogrammed for quick and efficient iterations during design development and debug cycles, and can be programmed and erased up to 100 times.

## Programmable Interconnect Array

Logic is routed between LABs via the programmable interconnect array (PIA). This global bus is a programmable path that connects any signal source to any destination on the device. All MAX 7000 dedicated inputs, I/O pins, and macrocell outputs feed the PIA, which makes the signals available throughout the entire device. Only the signals required by each LAB are actually routed from the PIA into the LAB. Figure 7 shows how the PIA signals are routed into the LAB. An EEPROM cell controls one input to a 2-input AND gate, which selects a PIA signal to drive into the LAB.

Figure 7. PIA Routing



While the routing delays of channel-based routing schemes in masked or FPGAs are cumulative, variable, and path-dependent, the MAX 7000 PIA has a fixed delay. The PIA thus eliminates skew between signals and makes timing performance easy to predict.

#### I/O Control Blocks

The I/O control block allows each I/O pin to be individually configured for input, output, or bidirectional operation. All I/O pins have a tri-state buffer that is individually controlled by one of the global output enable signals or directly connected to ground or V<sub>CC</sub>. Figure 8 shows the I/O control block for the MAX 7000 family. The I/O control block of EPM7032, EPM7064, and EPM7096 devices has two global output enable signals that are driven by two dedicated active-low output enable pins (OE1 and OE2). The I/O control block of MAX 7000E and MAX 7000S devices has six global output enable signals that are driven by the true or complement of two output enable signals, a subset of the I/O pins, or a subset of the I/O macrocells.

# Programmable Speed/Power Control

MAX 7000 devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more, because most logic applications require only a small fraction of all gates to operate at maximum frequency.

The designer can program each individual macrocell in a MAX 7000 device for either high-speed (i.e., with the Turbo Bit<sup>TM</sup> option turned on) or low-power (i.e., with the Turbo Bit option turned off) operation. As a result, speed-critical paths in the design can run at high speed, while the remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder ( $t_{LPA}$ ) for the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ , and  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters.

# Output Configuration

MAX 7000 device outputs can be programmed to meet a variety of system-level requirements.

### MultiVolt I/O Interface

MAX 7000 devices—except 44-pin devices—support the MultiVolt I/O interface feature, which allows MAX 7000 devices to interface with systems that have differing supply voltages. The 5.0-V devices in all packages can be set for 3.3-V or 5.0-V I/O pin operation. These devices have one set of VCC pins for internal operation and input buffers (VCCINT), and another set for I/O output drivers (VCCIO).

The VCCINT pins must always be connected to a 5.0-V power supply. With a 5.0-V  $V_{\rm CCINT}$  level, input voltage thresholds are at TTL levels, and are therefore compatible with both 3.3-V and 5.0-V inputs.

The VCCIO pins can be connected to either a 3.3-V or a 5.0-V power supply, depending on the output requirements. When the VCCIO pins are connected to a 5.0-V supply, the output levels are compatible with 5.0-V systems. When  $V_{\rm CCIO}$  is connected to a 3.3-V supply, the output high is 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with  $V_{\rm CCIO}$  levels lower than 4.75 V incur a nominally greater timing delay of  $t_{\rm OD2}$  instead of  $t_{\rm OD1}$ .

# Open-Drain Output Option (MAX 7000S Devices Only)

MAX 7000S devices provide an optional open-drain (functionally equivalent to open-collector) output for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write enable signals) that can be asserted by any of several devices. It can also provide an additional wired-OR plane.

# IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

MAX 7000 devices support JTAG BST circuitry as specified by IEEE Std. 1149.1-1990. Table 9 describes the JTAG instructions supported by the MAX 7000 family. The pin-out tables (see the Altera web site (http://www.altera.com) or the *Altera Digital Library* for pin-out information) show the location of the JTAG control pins for each device. If the JTAG interface is not required, the JTAG pins are available as user I/O pins.

Table 9. MAX 7000 J	ITAG Instruction	s
JTAG Instruction	Devices	Description
SAMPLE/PRELOAD	EPM7128S EPM7160S EPM7192S	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern output at the device pins.
	EPM7256S	pattern output at the device pins.
EXTEST	EPM7128S EPM7160S EPM7192S EPM7256S	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through a selected device to adjacent devices during normal device operation.
IDCODE	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
ISP Instructions	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	These instructions are used when programming MAX 7000S devices via the JTAG ports with the MasterBlaster, ByteBlasterMV, BitBlaster download cable, or using a Jam File (.jam), Jam Byte-Code file (.jbc), or Serial Vector Format file (.svf) via an embedded processor or test equipment.

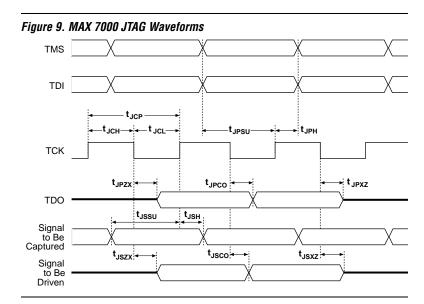


Figure 9 shows the timing requirements for the JTAG signals.

Table 12 shows the JTAG timing parameters and values for MAX 7000S devices.

Table 1	Table 12. JTAG Timing Parameters & Values for MAX 7000S Devices						
Symbol	Parameter	Min	Max	Unit			
t <sub>JCP</sub>	TCK clock period	100		ns			
t <sub>JCH</sub>	TCK clock high time	50		ns			
t <sub>JCL</sub>	TCK clock low time	50		ns			
t <sub>JPSU</sub>	JTAG port setup time	20		ns			
t <sub>JPH</sub>	JTAG port hold time	45		ns			
t <sub>JPCO</sub>	JTAG port clock to output		25	ns			
t <sub>JPZX</sub>	JTAG port high impedance to valid output		25	ns			
t <sub>JPXZ</sub>	JTAG port valid output to high impedance		25	ns			
t <sub>JSSU</sub>	Capture register setup time	20		ns			
t <sub>JSH</sub>	Capture register hold time	45		ns			
t <sub>JSCO</sub>	Update register clock to output		25	ns			
t <sub>JSZX</sub>	Update register high impedance to valid output		25	ns			
t <sub>JSXZ</sub>	Update register valid output to high impedance		25	ns			



For more information, see *Application Note* 39 (*IEEE 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices*).

# Operating Conditions

Tables 13 through 18 provide information about absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for 5.0-V MAX 7000 devices.

Table 1	Table 13. MAX 7000 5.0-V Device Absolute Maximum Ratings   Note (1)								
Symbol	Parameter	Conditions	Min	Max	Unit				
V <sub>CC</sub>	Supply voltage	With respect to ground (2)	-2.0	7.0	V				
VI	DC input voltage		-2.0	7.0	V				
I <sub>OUT</sub>	DC output current, per pin		-25	25	mA				
T <sub>STG</sub>	Storage temperature	No bias	-65	150	° C				
T <sub>AMB</sub>	Ambient temperature	Under bias	-65	135	° C				
TJ	Junction temperature	Ceramic packages, under bias		150	°C				
		PQFP and RQFP packages, under bias		135	°C				

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CCINT</sub>	Supply voltage for internal logic and input buffers	(3), (4), (5)	4.75 (4.50)	5.25 (5.50)	V
V <sub>CCIO</sub>	Supply voltage for output drivers, 5.0-V operation	(3), (4)	4.75 (4.50)	5.25 (5.50)	V
	Supply voltage for output drivers, 3.3-V operation	(3), (4), (6)	3.00 (3.00)	3.60 (3.60)	V
V <sub>CCISP</sub>	Supply voltage during ISP	(7)	4.75	5.25	V
V <sub>I</sub>	Input voltage		-0.5 (8)	V <sub>CCINT</sub> + 0.5	V
Vo	Output voltage		0	V <sub>CCIO</sub>	V
T <sub>A</sub>	Ambient temperature	For commercial use	0	70	°C
		For industrial use	-40	85	°C
TJ	Junction temperature	For commercial use	0	90	°C
		For industrial use	-40	105	° C
t <sub>R</sub>	Input rise time			40	ns
t <sub>F</sub>	Input fall time			40	ns

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>IH</sub>	High-level input voltage		2.0	V <sub>CCINT</sub> + 0.5	V
V <sub>IL</sub>	Low-level input voltage		-0.5 (8)	0.8	V
V <sub>OH</sub>	5.0-V high-level TTL output voltage	I <sub>OH</sub> = -4 mA DC, V <sub>CCIO</sub> = 4.75 V (10)	2.4		V
	3.3-V high-level TTL output voltage	I <sub>OH</sub> = -4 mA DC, V <sub>CCIO</sub> = 3.00 V (10)	2.4		V
	3.3-V high-level CMOS output voltage	$I_{OH} = -0.1 \text{ mA DC}, V_{CCIO} = 3.0 \text{ V} (10)$	V <sub>CCIO</sub> - 0.2		V
V <sub>OL</sub>	5.0-V low-level TTL output voltage	I <sub>OL</sub> = 12 mA DC, V <sub>CCIO</sub> = 4.75 V (11)		0.45	V
	3.3-V low-level TTL output voltage	I <sub>OL</sub> = 12 mA DC, V <sub>CCIO</sub> = 3.00 V (11)		0.45	V
	3.3-V low-level CMOS output voltage	$I_{OL} = 0.1 \text{ mA DC}, V_{CCIO} = 3.0 \text{ V}(11)$		0.2	V
lı	Leakage current of dedicated input pins	$V_I = -0.5 \text{ to } 5.5 \text{ V } (11)$	-10	10	μА
l <sub>OZ</sub>	I/O pin tri-state output off-state current	$V_I = -0.5 \text{ to } 5.5 \text{ V } (11), (12)$	-40	40	μА

Table 1	6. MAX 7000 5.0-V Device Capa	ncitance: EPM7032, EPM7064 & EPM7	7096 Devices	Note (1	3)
Symbol	Parameter	Conditions	Min	Max	Unit
C <sub>IN</sub>	Input pin capacitance	V <sub>IN</sub> = 0 V, f = 1.0 MHz		12	pF
C <sub>I/O</sub>	I/O pin capacitance	V <sub>OUT</sub> = 0 V, f = 1.0 MHz		12	pF

Table 1	7. MAX 7000 5.0-V Device Capa	acitance: MAX 7000E Devices Note	(13)		
Symbol	Parameter	Conditions	Min	Max	Unit
C <sub>IN</sub>	Input pin capacitance	V <sub>IN</sub> = 0 V, f = 1.0 MHz		15	pF
C <sub>I/O</sub>	I/O pin capacitance	V <sub>OUT</sub> = 0 V, f = 1.0 MHz		15	pF

Table 1	8. MAX 7000 5.0-V Device Capa	acitance: MAX 7000S Devices Note	(13)		
Symbol	Parameter	Conditions	Min	Max	Unit
C <sub>IN</sub>	Dedicated input pin capacitance	V <sub>IN</sub> = 0 V, f = 1.0 MHz		10	pF
C <sub>I/O</sub>	I/O pin capacitance	V <sub>OUT</sub> = 0 V, f = 1.0 MHz		10	pF

#### Notes to tables:

- (1) See the Operating Requirements for Altera Devices Data Sheet.
- (2) Minimum DC input voltage on I/O pins is –0.5 V and on 4 dedicated input pins is –0.3 V. During transitions, the inputs may undershoot to –2.0 V or overshoot to 7.0 V for input currents less than 100 mA and periods shorter than 20 ns.
- (3) Numbers in parentheses are for industrial-temperature-range devices.
- (4)  $V_{CC}$  must rise monotonically.
- (5) The POR time for all 7000S devices does not exceed 300 μs. The sufficient V<sub>CCINT</sub> voltage level for POR is 4.5 V. The device is fully initialized within the POR time after V<sub>CCINT</sub> reaches the sufficient POR voltage level.
- (6) 3.3-V I/O operation is not available for 44-pin packages.
- (7) The V<sub>CCISP</sub> parameter applies only to MAX 7000S devices.
- (8) During in-system programming, the minimum DC input voltage is –0.3 V.
- (9) These values are specified under the MAX 7000 recommended operating conditions in Table 14 on page 26.
- (10) The parameter is measured with 50% of the outputs each sourcing the specified current. The I<sub>OH</sub> parameter refers to high-level TTL or CMOS output current.
- (11) The parameter is measured with 50% of the outputs each sinking the specified current. The I<sub>OL</sub> parameter refers to low-level TTL, PCI, or CMOS output current.
- (12) When the JTAG interface is enabled in MAX 7000S devices, the input leakage current on the JTAG pins is typically -60 uA.
- (13) Capacitance is measured at 25° C and is sample-tested only. The OE1 pin has a maximum capacitance of 20 pF.

Figure 11 shows the typical output drive characteristics of MAX 7000 devices.

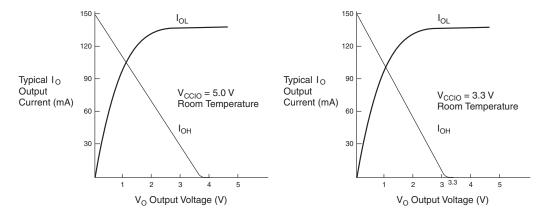
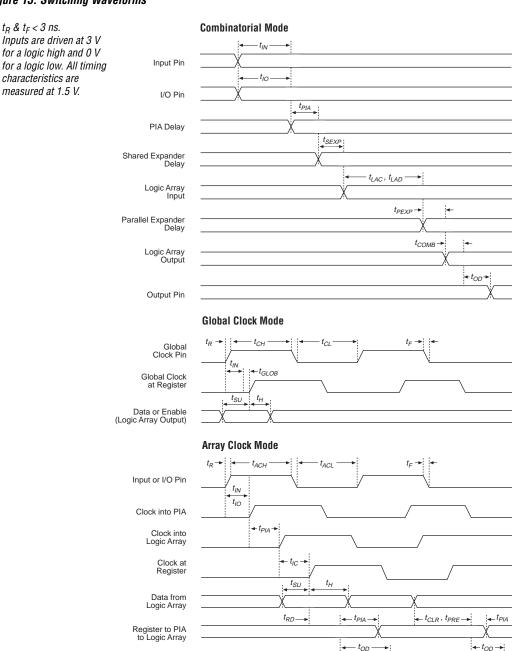


Figure 11. Output Drive Characteristics of 5.0-V MAX 7000 Devices

# **Timing Model**

MAX 7000 device timing can be analyzed with the Altera software, with a variety of popular industry-standard EDA simulators and timing analyzers, or with the timing model shown in Figure 12. MAX 7000 devices have fixed internal delays that enable the designer to determine the worst-case timing of any design. The Altera software provides timing simulation, point-to-point delay prediction, and detailed timing analysis for a device-wide performance evaluation.

## Figure 13. Switching Waveforms



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Register Output to Pin

Table 2	5. MAX 7000 & MAX 7000E	External Timing I	Paramete	ers /	lote (1)				
Symbol	Parameter	Conditions	Speed Grade						Unit
			-	15	-1	5T	-2	20	
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>SU</sub>	Global clock setup time		11.0		11.0		12.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input	(2)	3.0		-		5.0		ns
t <sub>FH</sub>	Global clock hold time of fast input	(2)	0.0		-		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		8.0		8.0		12.0	ns
t <sub>CH</sub>	Global clock high time		5.0		6.0		6.0		ns
t <sub>CL</sub>	Global clock low time		5.0		6.0		6.0		ns
t <sub>ASU</sub>	Array clock setup time		4.0		4.0		5.0		ns
t <sub>AH</sub>	Array clock hold time		4.0		4.0		5.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>ACH</sub>	Array clock high time		6.0		6.5		8.0		ns
t <sub>ACL</sub>	Array clock low time		6.0		6.5		8.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	6.0		6.5		8.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			13.0		13.0		16.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(5)	76.9		76.9		62.5		MHz
t <sub>ACNT</sub>	Minimum array clock period			13.0		13.0		16.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(5)	76.9		76.9		62.5		MHz
f <sub>MAX</sub>	Maximum clock frequency	(6)	100		83.3	_	83.3	_	MHz

Symbol	Parameter	Conditions				Speed	Grade	!			Unit
			-	6	-	7	-1	10	-1	15	
			Min	Max	Min	Max	Min	Max	Min	Max	-
t <sub>IN</sub>	Input pad and buffer delay			0.2		0.5		0.5		2.0	ns
t <sub>IO</sub>	I/O input pad and buffer delay			0.2		0.5		0.5		2.0	ns
t <sub>FIN</sub>	Fast input delay			2.6		1.0		1.0		2.0	ns
t <sub>SEXP</sub>	Shared expander delay			3.7		4.0		5.0		8.0	ns
t <sub>PEXP</sub>	Parallel expander delay			1.1		0.8		0.8		1.0	ns
$t_{LAD}$	Logic array delay			3.0		3.0		5.0		6.0	ns
$t_{LAC}$	Logic control array delay			3.0		3.0		5.0		6.0	ns
t <sub>IOE</sub>	Internal output enable delay			0.7		2.0		2.0		3.0	ns
t <sub>OD1</sub>	Output buffer and pad delay	C1 = 35 pF		0.4		2.0		1.5		4.0	ns
t <sub>OD2</sub>	Output buffer and pad delay	C1 = 35 pF (6)		0.9		2.5		2.0		5.0	ns
t <sub>OD3</sub>	Output buffer and pad delay	C1 = 35 pF		5.4		7.0		5.5		8.0	ns
t <sub>ZX1</sub>	Output buffer enable delay	C1 = 35 pF		4.0		4.0		5.0		6.0	ns
t <sub>ZX2</sub>	Output buffer enable delay	C1 = 35 pF (6)		4.5		4.5		5.5		7.0	ns
$t_{ZX3}$	Output buffer enable delay	C1 = 35 pF		9.0		9.0		9.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0		6.0	ns
t <sub>SU</sub>	Register setup time		1.0		3.0		2.0		4.0		ns
t <sub>H</sub>	Register hold time		1.7		2.0		5.0		4.0		ns
t <sub>FSU</sub>	Register setup time of fast input		1.9		3.0		3.0		2.0		ns
t <sub>FH</sub>	Register hold time of fast input		0.6		0.5		0.5		1.0		ns
$t_{RD}$	Register delay			1.4		1.0		2.0		1.0	ns
t <sub>COMB</sub>	Combinatorial delay			1.0		1.0		2.0		1.0	ns
t <sub>IC</sub>	Array clock delay			3.1		3.0		5.0		6.0	ns
t <sub>EN</sub>	Register enable time			3.0		3.0		5.0		6.0	ns
$t_{GLOB}$	Global control delay			2.0		1.0		1.0		1.0	ns
t <sub>PRE</sub>	Register preset time			2.4		2.0		3.0		4.0	ns
t <sub>CLR</sub>	Register clear time			2.4		2.0		3.0		4.0	ns
$t_{PIA}$	PIA delay	(7)		1.4		1.0		1.0		2.0	ns
$t_{LPA}$	Low-power adder	(8)		11.0		10.0		11.0		13.0	ns

#### Notes to tables:

- These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The t<sub>LPA</sub> parameter must be added to this minimum width if the clear or reset signal incorporates the t<sub>LAD</sub> parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The  $f_{MAX}$  values represent the highest frequency for pipelined data.
- (6) Operating conditions:  $V_{CCIO} = 3.3 \text{ V} \pm 10\%$  for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $\mathbf{t_{ACL}}$ , and  $\mathbf{t_{CPPW}}$  parameters for macrocells running in the low-power mode.

Tables 33 and 34 show the EPM7160S AC operating conditions.

Table 3	Table 33. EPM7160S External Timing Parameters (Part 1 of 2)   Note (1)										
Symbol	Parameter	Conditions	Speed Grade							Unit	
			-6		-7		-10		-15		
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		6.0		7.5		10.0		15.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		6.0		7.5		10.0		15.0	ns
t <sub>SU</sub>	Global clock setup time		3.4		4.2		7.0		11.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.5		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		3.9		4.8		5		8	ns
t <sub>CH</sub>	Global clock high time		3.0		3.0		4.0		5.0		ns
t <sub>CL</sub>	Global clock low time		3.0		3.0		4.0		5.0		ns
t <sub>ASU</sub>	Array clock setup time		0.9		1.1		2.0		4.0		ns
t <sub>AH</sub>	Array clock hold time		1.7		2.1		3.0		4.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		6.4		7.9		10.0		15.0	ns
t <sub>ACH</sub>	Array clock high time		3.0		3.0		4.0		6.0		ns
t <sub>ACL</sub>	Array clock low time		3.0		3.0		4.0		6.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(2)	2.5		3.0		4.0		6.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			6.7		8.2		10.0		13.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(4)	149.3		122.0		100.0		76.9		MHz

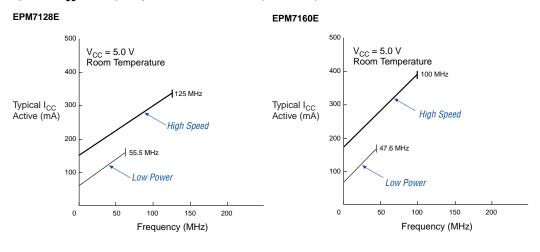
Tables 37 and 38 show the EPM7256S AC operating conditions.

Symbol	Parameter	Conditions	Speed Grade						
				7	-15		Unit		
			Min	Max	Min	IO Max	Min	Max	1
4	Innut to non variatored output	C4 25 pF	IVIIII	7.5	IVIIII	10.0	IVIIII	15.0	
t <sub>PD1</sub>	Input to non-registered output I/O input to non-registered output	C1 = 35 pF C1 = 35 pF		7.5		10.0		15.0	ns ns
t <sub>SU</sub>	Global clock setup time		3.9		7.0		11.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		3.0		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.5		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		4.7		5.0		8.0	ns
t <sub>CH</sub>	Global clock high time		3.0		4.0		5.0		ns
t <sub>CL</sub>	Global clock low time		3.0		4.0		5.0		ns
t <sub>ASU</sub>	Array clock setup time		0.8		2.0		4.0		ns
t <sub>AH</sub>	Array clock hold time		1.9		3.0		4.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		7.8		10.0		15.0	ns
t <sub>ACH</sub>	Array clock high time		3.0		4.0		6.0		ns
t <sub>ACL</sub>	Array clock low time		3.0		4.0		6.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(2)	3.0		4.0		6.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			7.8		10.0		13.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(4)	128.2		100.0		76.9		MHz
t <sub>ACNT</sub>	Minimum array clock period			7.8		10.0		13.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(4)	128.2		100.0		76.9		MHz
f <sub>MAX</sub>	Maximum clock frequency	(5)	166.7		125.0		100.0		MHz

Table 39. MAX 7000 I <sub>CC</sub> Equation Constants								
Device	Α	В	С					
EPM7032	1.87	0.52	0.144					
EPM7064	1.63	0.74	0.144					
EPM7096	1.63	0.74	0.144					
EPM7128E	1.17	0.54	0.096					
EPM7160E	1.17	0.54	0.096					
EPM7192E	1.17	0.54	0.096					
EPM7256E	1.17	0.54	0.096					
EPM7032S	0.93	0.40	0.040					
EPM7064S	0.93	0.40	0.040					
EPM7128S	0.93	0.40	0.040					
EPM7160S	0.93	0.40	0.040					
EPM7192S	0.93	0.40	0.040					
EPM7256S	0.93	0.40	0.040					

This calculation provides an  $I_{CC}$  estimate based on typical conditions using a pattern of a 16-bit, loadable, enabled, up/down counter in each LAB with no output load. Actual  $I_{CC}$  values should be verified during operation because this measurement is sensitive to the actual pattern in the device and the environmental operating conditions.

Figure 14. I<sub>CC</sub> vs. Frequency for MAX 7000 Devices (Part 2 of 2)



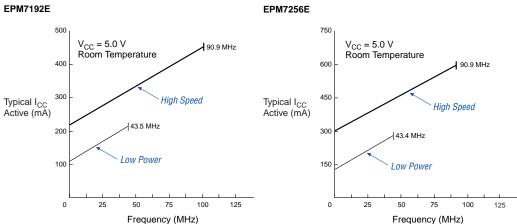
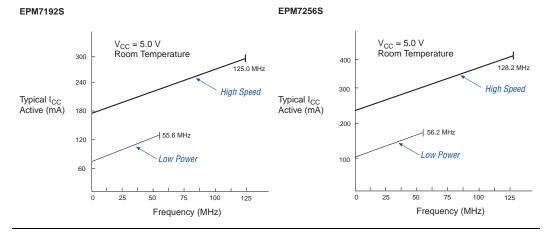


Figure 15. I<sub>CC</sub> vs. Frequency for MAX 7000S Devices (Part 2 of 2)



# Device Pin-Outs

See the Altera web site (http://www.altera.com) or the *Altera Digital Library* for pin-out information.

# Figure 21. 192-Pin Package Pin-Out Diagram

Package outline not drawn to scale.

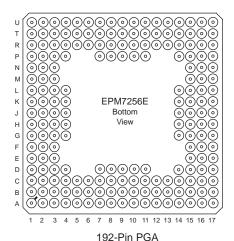
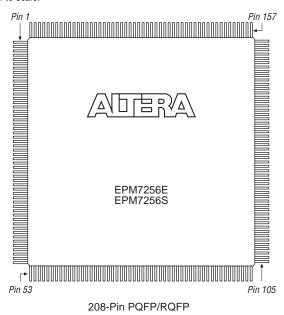


Figure 22. 208-Pin Package Pin-Out Diagram

Package outline not drawn to scale.



# Revision History

The information contained in the *MAX 7000 Programmable Logic Device Family Data Sheet* version 6.7 supersedes information published in previous versions. The following changes were made in the *MAX 7000 Programmable Logic Device Family Data Sheet* version 6.7:

### Version 6.7

The following changes were made in the MAX 7000 Programmable Logic Device Family Data Sheet version 6.7:

Reference to AN 88: Using the Jam Language for ISP & ICR via an Embedded Processor has been replaced by AN 122: Using Jam STAPL for ISP & ICR via an Embedded Processor.

## Version 6.6

The following changes were made in the MAX 7000 Programmable Logic Device Family Data Sheet version 6.6:

- Added Tables 6 through 8.
- Added "Programming Sequence" section on page 17 and "Programming Times" section on page 18.

## Version 6.5

The following changes were made in the MAX 7000 Programmable Logic Device Family Data Sheet version 6.5:

Updated text on page 16.

#### Version 6.4

The following changes were made in the MAX 7000 Programmable Logic Device Family Data Sheet version 6.4:

Added Note (5) on page 28.

#### Version 6.3

The following changes were made in the MAX 7000 Programmable Logic Device Family Data Sheet version 6.3:

■ Updated the "Open-Drain Output Option (MAX 7000S Devices Only)" section on page 20.



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